

SN54ABT162460, SN74ABT162460 4-TO-1 MULTIPLEXED/DEMULTIPLEXED REGISTERED TRANSCEIVERS WITH 3-STATE OUTPUTS

SCBS241A – FEBRUARY 1993 – REVISED JULY 1994

- B-Port Outputs Have Equivalent 25- Ω Series Resistors, So No External Resistors Are Required
- Members of the Texas Instruments *Widebus*™ Family
- State-of-the-Art *EPIC-II*™ BiCMOS Design Significantly Reduces Power Dissipation
- Typical V_{OLP} (Output Ground Bounce) < 1 V at $V_{CC} = 5$ V, $T_A = 25^\circ\text{C}$
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- Bus-Hold Inputs Eliminate the Need for External Pullup Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) Package and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

SN54ABT162460 . . . WD PACKAGE
SN74ABT162460 . . . DL PACKAGE
(TOP VIEW)

LEAB1	1	56	$\overline{\text{OEB1}}$
LEAB2	2	55	$\overline{\text{OEB2}}$
LEBA	3	54	SEL0
GND	4	53	GND
LEB1	5	52	1B1
LEB2	6	51	1B2
V_{CC}	7	50	V_{CC}
CLKBA	8	49	1B3
$\overline{\text{OEB}}$	9	48	1B4
CLKAB	10	47	2B1
GND	11	46	GND
1A	12	45	2B2
2A	13	44	2B3
CE_SEL0	14	43	2B4
CE_SEL1	15	42	3B1
3A	16	41	3B2
4A	17	40	3B3
GND	18	39	GND
$\overline{\text{CLKENAB}}$	19	38	3B4
$\overline{\text{CLKENB}}$	20	37	4B1
$\overline{\text{CLKENBA}}$	21	36	4B2
V_{CC}	22	35	V_{CC}
LEB3	23	34	4B3
LEB4	24	33	4B4
GND	25	32	GND
$\overline{\text{OEA}}$	26	31	SEL1
LEAB3	27	30	$\overline{\text{OEB3}}$
LEAB4	28	29	$\overline{\text{OEB4}}$

description

The 'ABT162460 are 4-bit-to-1-bit multiplexed registered transceivers used in applications where four separate data paths must be multiplexed onto or demultiplexed from a single data path. Typical applications include multiplexing and/or demultiplexing of address and data information in microprocessor or bus-interface applications. This device is also useful in memory-interleaving applications.

Five 4-bit I/O ports (1A–4A, 1B1–4, 2B1–4, 3B1–4, and 4B1–4) are available for address and/or data transfer. The output-enable ($\overline{\text{OEB}}$, $\overline{\text{OEB1}}$ – $\overline{\text{OEB4}}$, and $\overline{\text{OEA}}$) inputs control the bus transceiver functions. These control signals also allow 4-bit or 16-bit control depending on the $\overline{\text{OEB}}$ level.

Address and/or data information can be stored using the internal storage latches/flip-flops. The latch-enable (LEB1–LEB4, LEBA, and LEAB1–LEAB4) and clock/clock-enable (CLK/CLKEN) inputs are used to control data storage. When either one of the latch-enable inputs is high, the latch is transparent (clock is a don't care as long as the latch-enable is high). When the latch-enable input goes low (providing that the clock does not transit from low to high), the data present at the inputs is latched and remains latched until the latch-enable input is returned high. When the clock-enable is low and the corresponding latch-enable is low, data can be clocked on the low to high transition of the clock. When either the clock-enable or the corresponding latch-enable is high, the clock is a don't care.

Four select (SEL0, SEL1, CE_SEL0, and CE_SEL1) pins are provided to multiplex data (A port), or to select one of four clock-enables (B port). This allows the user to have the flexibility of controlling one bit at a time.

The B-port outputs, which are designed to sink up to 12 mA, include 25- Ω series resistors to reduce overshoot and undershoot.

Active bus-hold circuitry is provided to hold unused or floating inputs at a valid logic level.

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SN54ABT162460, SN74ABT162460

4-TO-1 MULTIPLEXED/DEMULTIPLEXED REGISTERED TRANSCEIVERS

WITH 3-STATE OUTPUTS

SCBS241A – FEBRUARY 1993 – REVISED JULY 1994

description (continued)

To ensure the high-impedance state during power-up or power-down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ABT162460 is available in TI's shrink small-outline package (DL), which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The SN54ABT162460 is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74ABT162460 is characterized for operation from -40°C to 85°C .

Function Tables

A-TO-B OUTPUT ENABLE†

INPUTS		OUTPUT Bn
\overline{OEB}	\overline{OEBn}	
H	H	Z
H	L	Z
L	H	Z
L	L	Active

† n = 1, 2, 3, 4

A-TO-B STORAGE (assuming $\overline{OEB} = \text{L}$, $\overline{OEBn} = \text{L}$)‡

INPUTS								OUTPUTS			
$\overline{\text{CLKENAB}}$	CE_SEL1	CE_SEL0	CLKAB	LEAB1	LEAB2	LEAB3	LEAB4	B1	B2	B3	B4
X	X	X	H or L	H	L	L	L	A	A ₀	A ₀	A ₀
X	X	X	H or L	H	H	H	L	A	A	A	A ₀
L	X	X	L	L	L	L	L	A ₀	A ₀	A ₀	A ₀
L	L	L	↑	L	L	L	L	A	A ₀	A ₀	A ₀
L	L	H	↑	L	L	L	L	A ₀	A	A ₀	A ₀
L	H	L	↑	L	L	L	L	A ₀	A ₀	A	A ₀
L	H	H	↑	L	L	L	L	A ₀	A ₀	A ₀	A
H	X	X	↑	L	L	L	L	A ₀	A ₀	A ₀	A ₀

‡ This table does not cover all the latch-enable cases since they have similar results.



SN54ABT162460, SN74ABT162460
**4-TO-1 MULTIPLEXED/DEMULTIPLEXED REGISTERED TRANSCEIVERS
 WITH 3-STATE OUTPUTS**

SCBS241A – FEBRUARY 1993 – REVISED JULY 1994

Function Tables (Continued)

**B-TO-A STORAGE
 (before point P)**

INPUTS								P
CLKENB	CLKBA	LEB1	LEB2	LEB3	LEB4	SEL1	SEL0	
X	X	H	L	L	L	L	L	B1
X	X	L	H	L	L	L	H	B2
X	X	L	L	H	L	H	L	B3
X	X	L	L	L	H	H	H	B4
L ↑ L L L L						L	L	B1
						L	H	B2
						H	L	B3
						H	H	B4
L L L L L L						L	L	B1 [†]
						L	H	B2 [†]
						H	L	B3 [†]
						H	H	B4 [†]

† Output level before the indicated steady-state input conditions were established.

**B-TO-A STORAGE
 (after point P)**

INPUTS					OUTPUT A
CLKENB	CLKBA	LEBA	\overline{OEA}	B	
X	X	X	H	X	Z
X	X	H	L	L	L
X	X	H	L	H	H
H	X	L	L	X	A ₀ [†]
L	↑	L	L	L	L
L	↑	L	L	H	H
L	L	L	L	X	A ₀ [†]

† Output level before the indicated steady-state input conditions were established.

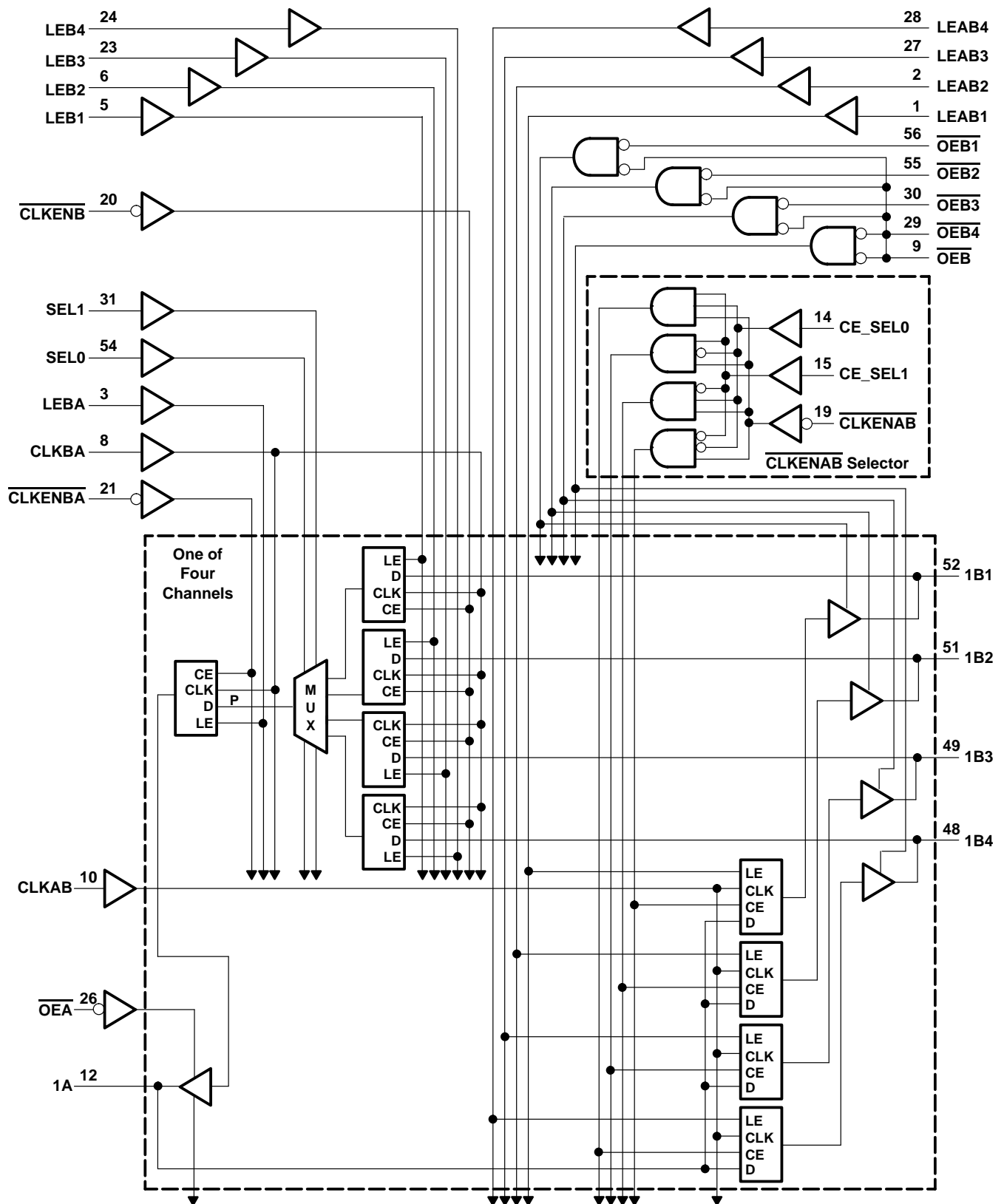
SN54ABT162460, SN74ABT162460

4-TO-1 MULTIPLEXED/DEMULTIPLEXED REGISTERED TRANSCEIVERS

WITH 3-STATE OUTPUTS

SCBS241A – FEBRUARY 1993 – REVISED JULY 1994

logic diagram (positive logic)



SN54ABT162460, SN74ABT162460

4-TO-1 MULTIPLEXED/DEMULTIPLEXED REGISTERED TRANSCEIVERS WITH 3-STATE OUTPUTS

SCBS241A – FEBRUARY 1993 – REVISED JULY 1994

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 7 V
Input voltage range, V_I (except I/O ports) (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high state or power-off state, V_O	–0.5 V to 5.5 V
Current into any output in the low state, I_O : SN54ABT162460 (A port)	96 mA
SN74ABT162460 (A port)	128 mA
B port	30 mA
Input clamp current, I_{IK} ($V_I < 0$)	–18 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Maximum power dissipation at $T_A = 55^\circ\text{C}$ (in still air) (see Note 2): DL package	1.4 W
Storage temperature range	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.
 For more information, refer to the *Package Thermal Considerations* application note in the 1994 *ABT Advanced BiCMOS Technology Data Book*, literature number SCBD002B.

recommended operating conditions (see Note 3)

			SN54ABT162460			SN74ABT162460			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC}	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
V _{IH}	High-level input voltage		2			2			V
V _{IL}	Low-level input voltage		0.8			0.8			V
V _I	Input voltage		0	V _{CC}		0	V _{CC}		V
I _{OH}	High-level output current	A port	−24			−32			mA
		B port	−12			−12			
I _{OL}	Low-level output current	A port	48			64			mA
		B port	12			12			
Δt/Δv	Input transition rise or fall rate	Outputs enabled	10			10			ns/V
Δt/ΔV _{CC}	Power-up ramp rate		200			200			μs/V
T _A	Operating free-air temperature		−55			125			°C
			−40			85			

NOTE 3: Unused or floating pins (input or I/O) must be held high or low.

SN54ABT162460, SN74ABT162460

4-TO-1 MULTIPLEXED/DEMULTIPLEXED REGISTERED TRANSCEIVERS

WITH 3-STATE OUTPUTS

SCBS241A – FEBRUARY 1993 – REVISED JULY 1994

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	SN54ABT162460			SN74ABT162460			UNIT
			MIN	TYP†	MAX	MIN	TYP†	MAX	
V_{IK}		$V_{CC} = 4.5\text{ V}$, $I_I = -18\text{ mA}$	-1.2			-1.2			V
V_{OH}	A port	$V_{CC} = 5\text{ V}$, $I_{OH} = -3\text{ mA}$	3	3.4		3	3.4		V
		$V_{CC} = 4.5\text{ V}$, $I_{OH} = -3\text{ mA}$	2.5	3					
		$V_{CC} = 4.5\text{ V}$, $I_{OH} = -32\text{ mA}$				2	2.7		
	B port	$V_{CC} = 5\text{ V}$, $I_{OH} = -1\text{ mA}$	3.8	4.2		4.2			
		$V_{CC} = 4.5\text{ V}$, $I_{OH} = -1\text{ mA}$	3.3	3.7		3.7			
		$V_{CC} = 4.5\text{ V}$, $I_{OH} = -3\text{ mA}$	3	3.6		3.6			
V_{OL}	A port	$V_{CC} = 4.5\text{ V}$, $I_{OL} = 24\text{ mA}$		0.25	0.55				V
		$V_{CC} = 4.5\text{ V}$, $I_{OL} = 64\text{ mA}$					0.3	0.55	
	B port	$V_{CC} = 4.5\text{ V}$, $I_{OL} = 8\text{ mA}$		0.4	0.8		0.4	0.65	
		$V_{CC} = 4.5\text{ V}$, $I_{OL} = 12\text{ mA}$					0.5	0.8	
I_I	Control inputs	$V_{CC} = 0\text{ to }5.5\text{ V}$, $V_I = V_{CC}\text{ or GND}$		± 1			± 1		μA
	A or B ports	$V_{CC} = 2.1\text{ V to }5.5\text{ V}$, $V_I = V_{CC}\text{ or GND}$		± 20			± 20		
$I_{I(\text{hold})}$	A or B ports	$V_{CC} = 5.5\text{ V}$, $V_I = 0.8\text{ V}$	75	500		75	500		μA
		$V_{CC} = 4.5\text{ V}$, $V_I = 2\text{ V}$	-75	-500		-75	-500		
$I_{O\ddagger}$	A port	$V_{CC} = 5.5\text{ V}$, $V_O = 2.5\text{ V}$	-50	-110	-180	-50	-180		mA
	B port	$V_{CC} = 5.5\text{ V}$, $V_O = 2.5\text{ V}$	-25	-55	-90	-25	-90		
		$V_{CC} = 5.5\text{ V}$, $V_O = 0$	-50	-110	-180	-50	-180		
I_{CEX}	Outputs high	$V_{CC} = 5.5\text{ V}$, $V_O = 5.5\text{ V}$		50			50		μA
I_{off}		$V_{CC} = 0$, $V_I\text{ or }V_O \leq 4.5\text{ V}$		± 100			± 100		μA
$I_{OZPU}\S$		$V_{CC} = 0\text{ to }2.1\text{ V}$, $V_O = 0.5\text{ V to }2.7\text{ V}$, $OE = X$		± 50			± 50		μA
$I_{OZPD}\S$		$V_{CC} = 2.1\text{ V to }0$, $V_O = 0.5\text{ V to }2.7\text{ V}$, $OE = X$		± 50			± 50		μA
$I_{OZH}\P$		$V_{CC} = 2.1\text{ V to }5.5\text{ V}$, $V_O = 2.7\text{ V}$, $OE \geq 2\text{ V}$		10			10		μA
$I_{OZL}\P$		$V_{CC} = 2.1\text{ V to }5.5\text{ V}$, $V_O = 0.5\text{ V}$, $OE \geq 2\text{ V}$		-10			-10		μA
I_{CC}	Outputs high	$V_{CC} = 5.5\text{ V}$, Outputs open		1.5			0.7	1.5	mA
	A port low			10			6	10	
	B port low			32			18	32	
	Outputs disabled			1.5			0.7	1.5	
$\Delta I_{CC}\#$		$V_{CC} = 5.5\text{ V}$, One input at 3.4 V, Other inputs at $V_{CC}\text{ or GND}$		1			1		mA
C_i	Control inputs	$V_I = 2.5\text{ V or }0.5\text{ V}$		3.5			3.5		pF
C_{io}	A or B ports	$V_O = 2.5\text{ V or }0.5\text{ V}$		8			8		pF

† All typical values are at $V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$.

‡ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

§ This parameter is characterized but not tested.

¶ The parameters I_{OZH} and I_{OZL} include the input leakage current.

This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

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SN54ABT162460, SN74ABT162460

4-TO-1 MULTIPLEXED/DEMULTIPLEXED REGISTERED TRANSCEIVERS WITH 3-STATE OUTPUTS

SCBS241A – FEBRUARY 1993 – REVISED JULY 1994

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)(see Figure 1)

			$V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$		SN54ABT162460		SN74ABT162460		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
f_{clock}	Clock frequency		0	160	0	160	0	160	MHz
t_w	Pulse duration	CLKAB high or low	3.8		3.8		3.8		ns
		CLKBA high or low	4.5		4.5		4.5		
		LEAB1, 2, 3, or 4 high	2.8		2.8		2.8		
		LEBA high	2.8		2.8		2.8		
		LEB1, 2, 3, or 4 high	3		3		3		
t_{su}	Before CLKAB \uparrow	A bus	2.5		2.5		2.5		ns
		CE_SEL0/1	3.2		3.2		3.2		
		CLKENAB	3.2		3.2		3.2		
	Before LEAB1, 2, 3, or 4 \downarrow	A bus	3.6		3.6		3.6		
		B bus	3.8		3.8		3.8		
		CLKENB	2.3		2.3		2.3		
	Before CLKBA \uparrow	CLKENBA	2.5		2.5		2.5		
		LEB1, 2, 3, or 4	4.3		4.3		4.3		
		SEL0/1	4.5		4.5		4.5		
	Before LEB1, 2, 3, or 4 \downarrow	B bus	3.2		3.2		3.2		
		B bus	4		4		4		
		LEB1, 2, 3, or 4	4.4		4.4		4.4		
	Before LEBA \downarrow	SEL0/1	4.3		4.3		4.3		
t_h	After CLKAB \uparrow	A bus	0.5		0.5		0.5		ns
		CE_SEL0/1	1.1		1.1		1.1		
		CLKENAB	0.5		0.5		0.5		
	After LEAB1, 2, 3, or 4 \downarrow	A bus	1.2		1.2		1.2		
		B bus	1.3		1.3		1.3		
		CLKENB	1		1		1		
	After CLKBA \uparrow	CLKENBA	1		1		1		
		SEL0/1	0		0		0		
	After LEB1, 2, 3, or 4 \downarrow	B bus	1.5		1.5		1.5		
		B bus	0.4		0.4		0.4		
		SEL0/1	0.1		0.1		0.1		

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switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50$ pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 5$ V, $T_A = 25^\circ\text{C}$			SN54ABT162460		SN74ABT162460		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
f_{\max}			160			160		160		MHz
t_{PLH}	B	A	2	3.6	5.9	2	7.1	2	6.5	ns
t_{PHL}			2	3.5	5.8	2	6.8	2	6.5	
t_{PZH}	\overline{OEA}	A	1.5	2.8	4.8	1.5	5.9	1.5	5.6	ns
t_{PZL}			1.5	2.6	4.8	1.5	5.7	1.5	5.5	
t_{PHZ}	\overline{OEA}	A	2	3.8	5.3	2	6	2	5.9	ns
t_{PLZ}			1.5	4	6.1	1.5	7	1.5	6.5	
t_{PLH}	A	B	2	3.3	5.5	2	6.5	2	6.2	ns
t_{PHL}			2	3.7	5.8	2	6.8	2	6.5	
t_{PZH}	\overline{OEB}	B	2	3.9	5.8	2	7.1	2	6.8	ns
t_{PZL}			2	3.7	5.6	2	6.6	1.5	6.3	
t_{PHZ}	\overline{OEB}	B	2	4	5.6	2	6.4	2	6.2	ns
t_{PLZ}			2	3.7	5.2	2	6.1	2	5.8	
t_{PZH}	$\overline{OEB1}, \overline{2}, \overline{3}, \overline{4}$	B	2	3.7	5.8	2	6.8	2	6.6	ns
t_{PZL}			2	3.5	5.4	2	6.4	2	6.2	
t_{PHZ}	$\overline{OEB1}, \overline{2}, \overline{3}, \overline{4}$	B	1.5	3.3	4.8	1.5	5.4	1.5	5.3	ns
t_{PLZ}			1.5	3.1	4.4	1.5	5.1	1.5	4.9	
t_{PLH}	CLKBA	A	1.5	4.2	6.7	1.5	8.1	1.5	7.4	ns
t_{PHL}			1.5	4.4	6.9	1.5	8.4	1.5	7.7	
t_{PLH}	CLKAB	B	2	3.5	5.8	2	6.9	2	6.5	ns
t_{PHL}			2	3.7	6	2	7	2	6.5	
t_{PLH}	LEBA	A	1.5	3	5.2	1.5	6.3	1.5	5.8	ns
t_{PHL}			1.5	3	5	1.5	6.3	1.5	5.8	
t_{PLH}	LEAB1, 2, 3, 4	B	2	3.4	5.4	2	6.5	2	6.2	ns
t_{PHL}			2	3.6	5.7	2	6.3	2	6.2	
t_{PLH}	LEBA1, 2, 3, 4	A	2	4	6.5	2	7.8	2	7.2	ns
t_{PHL}			2	4	6.1	2	7.5	2	6.8	
t_{PLH}	SEL	A	2	4.1	6.7	2	8.1	2	7.5	ns
t_{PHL}			2	3.8	6.2	2	7.3	2	6.9	

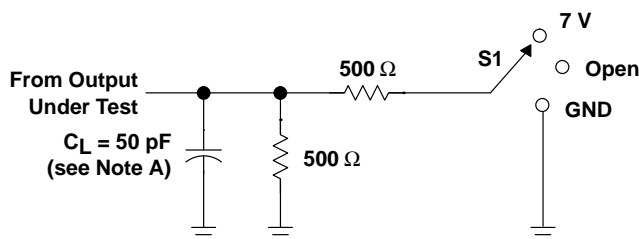
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4-TO-1 MULTIPLEXED/DEMULTIPLEXED REGISTERED TRANSCEIVERS

WITH 3-STATE OUTPUTS

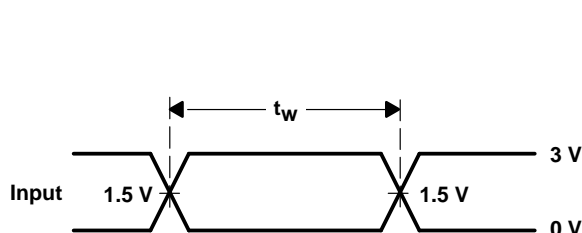
SCBS241A – FEBRUARY 1993 – REVISED JULY 1994

PARAMETER MEASUREMENT INFORMATION

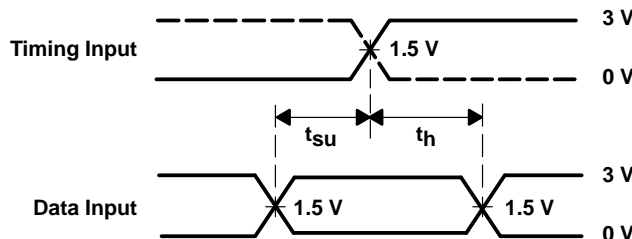


TEST	S1
t _{PLH} /t _{PHL}	Open
t _{PLZ} /t _{PZL}	7 V
t _{PHZ} /t _{PZH}	Open

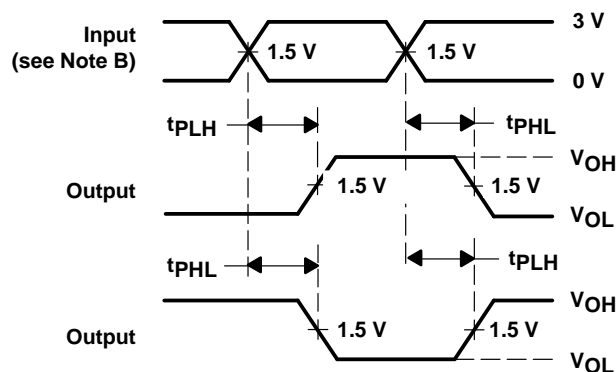
LOAD CIRCUIT FOR OUTPUTS



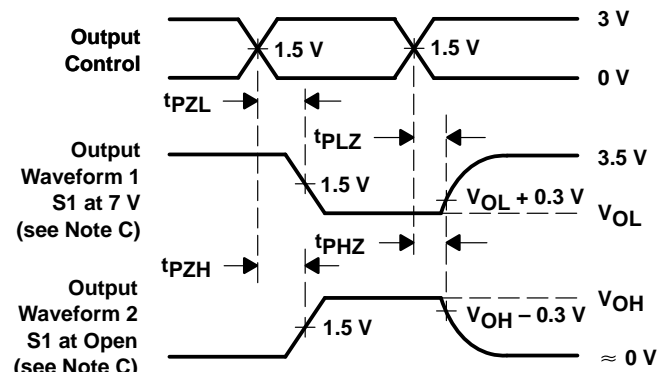
VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES
INVERTING AND NONINVERTING OUTPUTS



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES
LOW- AND HIGH-LEVEL ENABLING

- NOTES:
- C_L includes probe and jig capacitance.
 - All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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